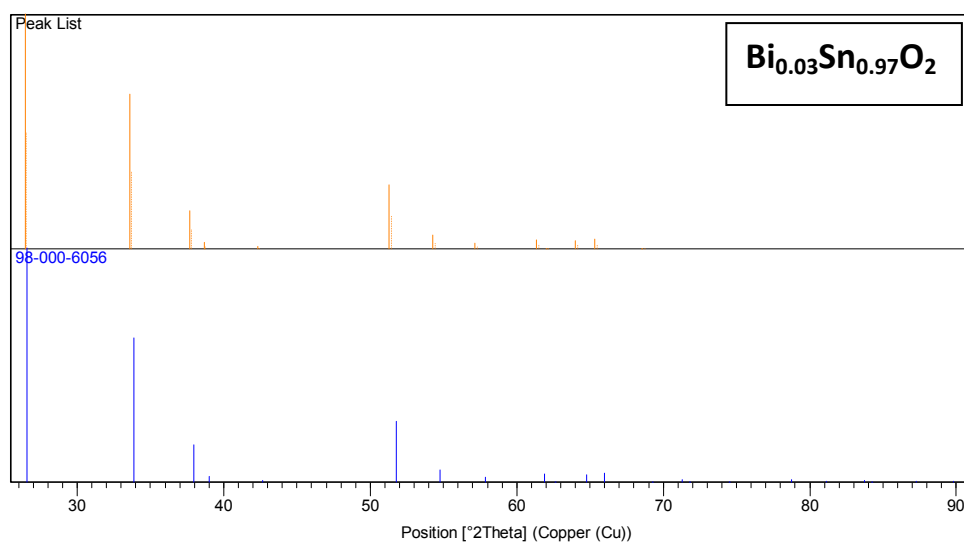
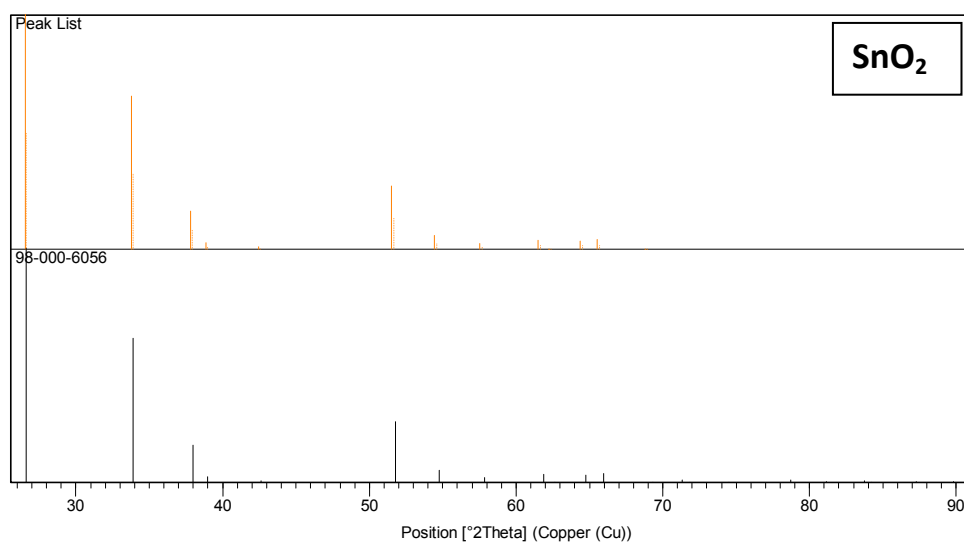
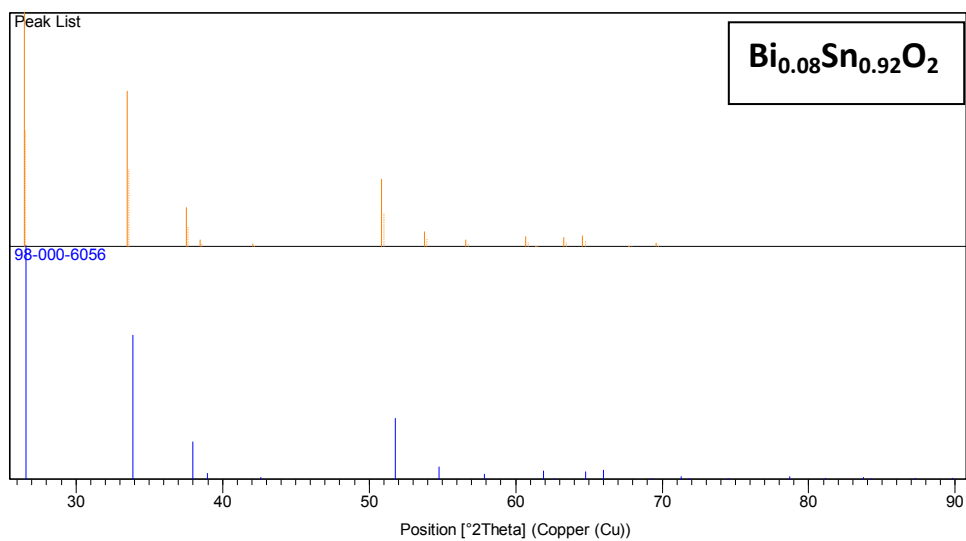
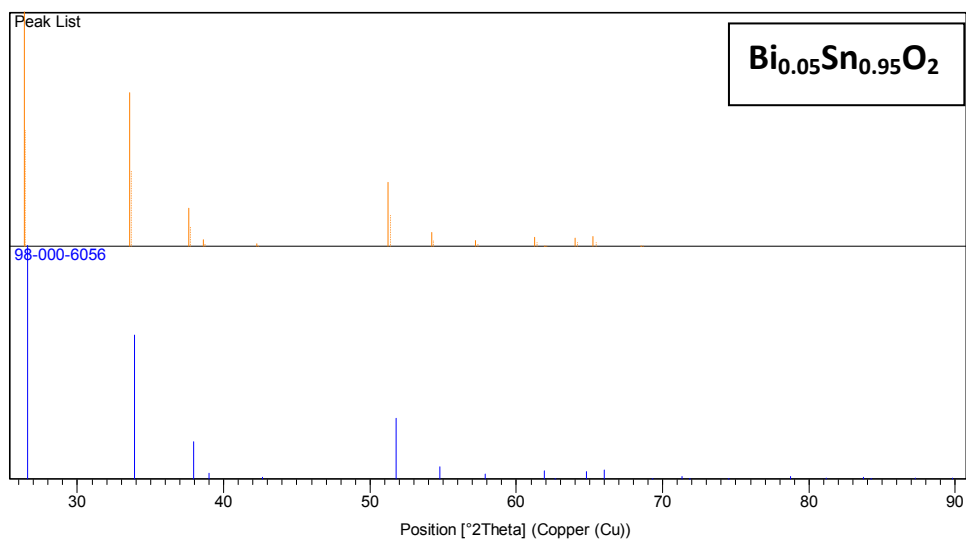


SUPPORTING INFORMATION

S1

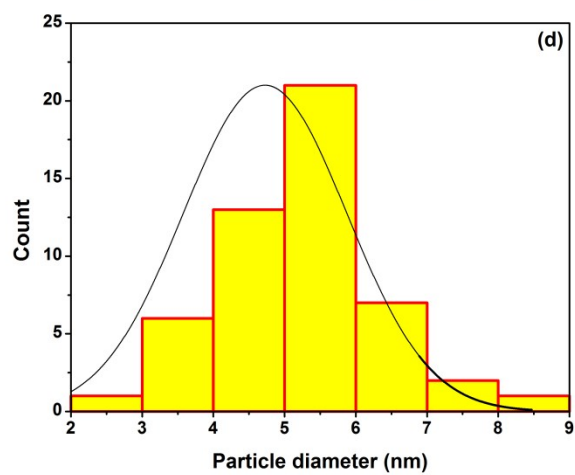
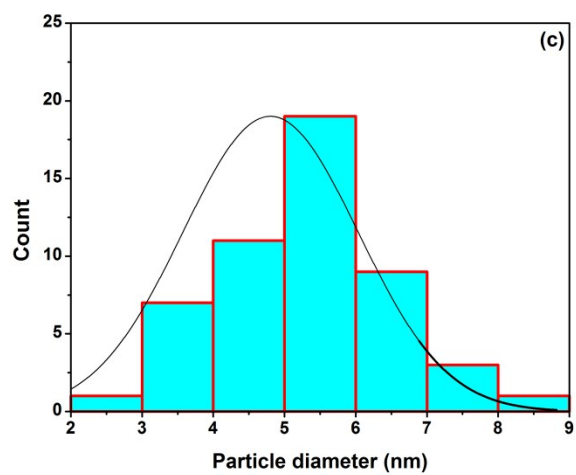
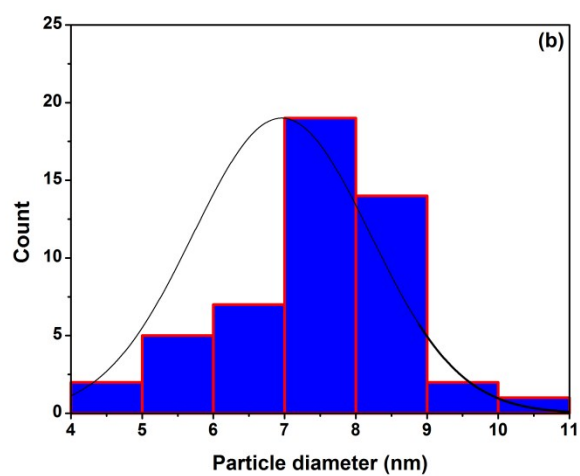
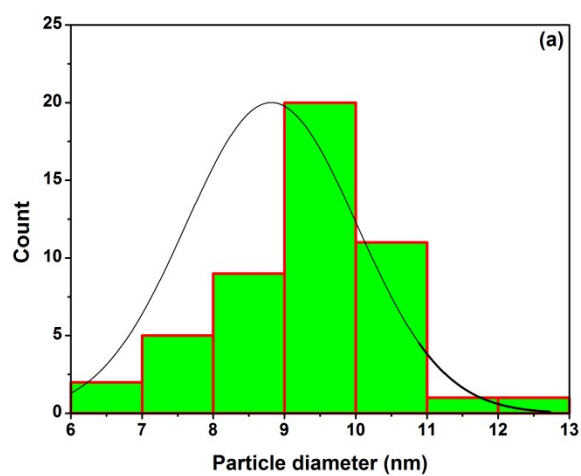
The peak refinement of XRD - Rietveld powder structure refinement method by using PANalytical X'Pert High Score Plus software





S2

Particle size distribution histogram (a) SnO_2 (b) $\text{Bi}_{0.03}\text{Sn}_{0.97}\text{O}_2$ (c) $\text{Bi}_{0.05}\text{Sn}_{0.95}\text{O}_2$ and (d) $\text{Bi}_{0.08}\text{Sn}_{0.92}\text{O}_2$ ultrananocrystalline particles



S3

XPS Survey spectrum of SnO₂

